

<b>Notice of References Cited</b>	Application/Control No. 09/871,527		Applicant(s)/Patent Under Reexamination VON DREELE ET AL.	
	Examiner Carolyn L Smith		Art Unit 1631	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,667,299 B1	12-2003	Ahlem et al.	514/178
	C	US-			
	D	US-			
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	F	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Heiney. "What is X-ray diffraction (XRD)", 1996, on the world wide web at <a href="http://dept.physics.upenn.edu/~heiney/talks/hires/whatis.html#SECTION00014000000000000000">http://dept.physics.upenn.edu/~heiney/talks/hires/whatis.html#SECTION00014000000000000000</a> , 4 pages.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.